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PATENT & TRADEMARK OFFICE
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PATENT APPLICATION

Sheet 1 of 2

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO.	APPLICATION NO.	CONFIRMATION NO.
200312936-1	10/606,715	5780
APPLICANT	Benjamin T. Percer et al.	
FILING DATE	GROUP	
06-26-2003	2863	

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
TL	1A 5,157,326	Oct. 20, 1992	BURNSIDES	
	1B 6,476,615	Nov. 05, 2002	MARBOT ET AL.	
	1C 6,563,350	May 13, 2003	WARNER ET AL.	
	1D 6,564,350	May 13, 2003	HOEWELER	
↓	1E 6,697,952	Feb. 24, 2004	KING	
	1F			
	1G			
	1H			
	1I			
	1J			
	1K			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
TL	1L JP/62-262165	11-14-1987	NIPPON ELECTRIC		
TL	1M EP/0 505 120	09-23-1992	AMDAHL		
TL	1N JP/5-2502	01-08-1993	NIPPON ELECTRIC		
TL	1O GB/1 219 001	01-13-1971	INDUSTRIAL NUCLEONIC		
	1P				

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

TL	1Q	Great Britain Search Report. Application No. GB0413503.4. October 27, 2004.
TL	1R	Great Britain Search Report. Application No. GB0413502.6. November 9, 2004.
TL	1S	Great Britain Search Report. Application No. GB 0413501.8. November 5, 2004.

EXAMINER

John Se

DATE CONSIDERED

05/05/2005



PATENT APPLICATION

Sheet 2 of 2

FORM PTO-1449

LIST OF PATENTS AND PUBLICATIONS FOR
APPLICANT'S INFORMATION DISCLOSURE
STATEMENT

(Use several sheets if necessary)

ATTY. DOCKET NO. 200208051-1	APPLICATION NO. 10/606,463	CONFIRMATION NO.
APPLICANT Benjamin T. Percer et al.	10/606,463	JL
FILING DATE 06-26-2003	GROUP 2863	

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
2A				
2B				
2C				
2D				
2E				
2F				
2G				
2H				
2I				
2J				
2K				

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
2L					
2M					
2N					
2O					
2P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

2Q	Berner, et al. "DC Voltage Margin Tester. NB84092465. IBM Technical Disclosure Bulletin, Vol. 27, No. 4B, September 1984, pg. 246.
2R	Tsukude, et al. "Highly Reliable Testing of ULSI Memories with On-Chip Voltage-Down Converters". IEEE Design & Test Computers. June 1993, pgs. 6-12.
2S	

EXAMINER

DATE CONSIDERED

05/05/2005